

REFERENCES

- [1] Döttling, M., Mohr, W., and Osseiran, A. (2009). *Radio technologies and concepts for IMT-advanced*. John Wiley & Sons.
- [2] ETSI (2018). Study on channel model for frequencies from 0.5 to 100 ghz. Technical report, 3GPP.
- [3] Goldsmith, A. (2005). *Wireless communications*. Cambridge university press.
- [4] Lee, W. C. (2010). *Mobile communications design fundamentals*. John Wiley & Sons.
- [5] Maccartney, G. R., Rappaport, T. S., Sun, S., and Deng, S. (2015). Indoor office wideband millimeter-wave propagation measurements and channel models at 28 and 73 ghz for ultra-dense 5g wireless networks. *IEEE access*, 3:2388–2424.
- [6] Naseem, Z., Nausheen, I., and Mirza, Z. (2018). Propagation models for wireless communication system. *signal*, 5(01).
- [7] Rappaport, T. S. (2002). Wireless communications—principles and practice, (the book end). *Microwave Journal*, 45(12):70–132.
- [8] Rappaport, T. S., MacCartney, G. R., Samimi, M. K., and Sun, S. (2015). Wide-band millimeter-wave propagation measurements and channel models for future wireless communication system design. *IEEE transactions on Communications*, 63(9):3029–3056.
- [9] Samimi, M. K. and Rappaport, T. S. (2016). 3-d millimeter-wave statistical channel model for 5g wireless system design. *IEEE Transactions on Microwave Theory and Techniques*, 64(7):2207–2225.
- [10] Semire, F., Akande, A., and Adele, O. (2015). Evaluation of suitable propagation model for 4g lte communication in nigeria. *LAUTECH Journal of Engineering and Technology*, 10(1):32–40.
- [11] Sufyan, A., Khan, K. B., Khashan, O. A., Mir, T., and Mir, U. (2023). From 5g to beyond 5g: A comprehensive survey of wireless network evolution, challenges, and promising technologies. *Electronics*, 12(10):2200.
- [12] Sun, S., Rappaport, T. S., Rangan, S., Thomas, T. A., Ghosh, A., Kovacs, I. Z., Rodriguez, I., Koymen, O., Partyka, A., and Jarvelainen, J. (2016). Propagation path loss models for 5g urban micro-and macro-cellular scenarios. In *2016 IEEE 83rd Vehicular Technology Conference (VTC Spring)*, pages 1–6. IEEE.